

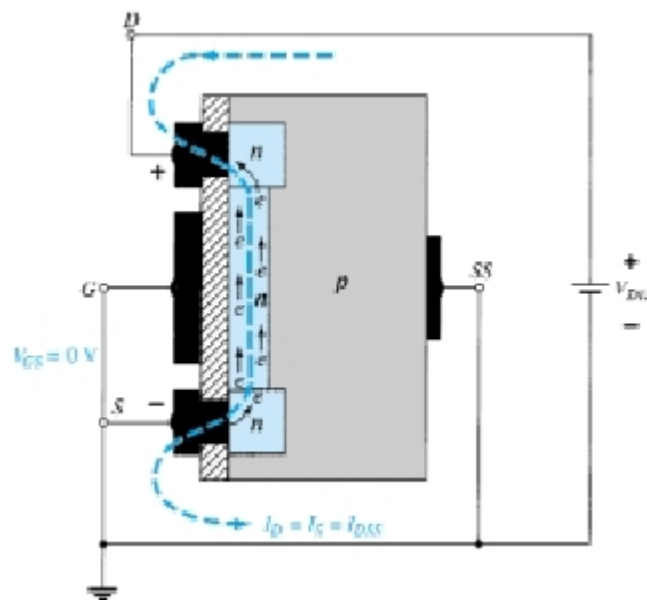
## MOSFET

There are two types of FETs: JFETs and MOS-FETs. MOSFETs are further broken down into depletion type and enhancement type. The terms depletion and enhancement define their basic mode of operation, while the label MOSFET stands for metal-oxide-semiconductor-field-effect transistor. Since there are differences in the characteristics and operation of each type of MOSFET, they are covered in separate sections. In this section we examine the depletion-type MOSFET, which happens to have characteristics similar to those of a JFET between cutoff and saturation at  $I_{DSS}$  but then has the added feature of characteristics that extend into the region of opposite polarity for  $V_{GS}$ .

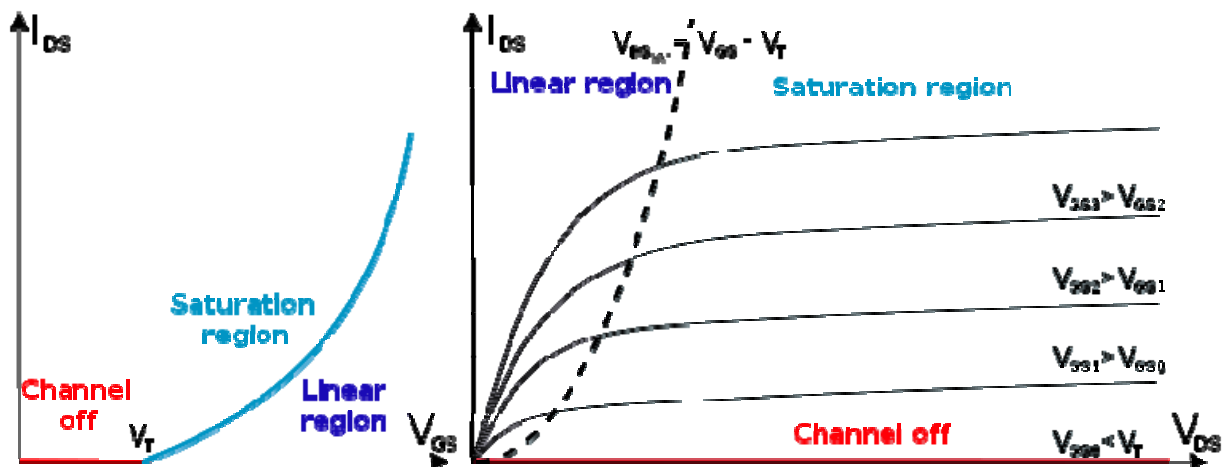
### depletion type mosfet

#### Basic Operation and Characteristics

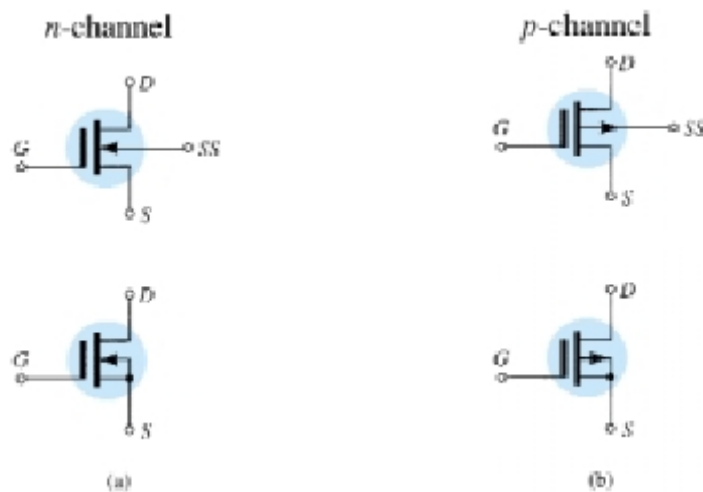
In the gate-to-source voltage is set to zero volts by the direct connection from one terminal to the other, and a voltage  $V_{DS}$  is applied across the drain-to-source terminals. The result is an attraction for the positive potential at the drain by the free electrons of the n-channel and a current similar to that established through the channel of the JFET. In fact, the resulting current with  $V_{GS} = 0$ , as shown in Fig



$V_{GS}$  has been set at a negative voltage such as The negative potential at the gate will tend to pressure electrons toward the p-type substrate (like charges repel) and attract holes from the p-type substrate (opposite charges attract) as shown in Fig. 5.26. Depending on the magnitude of the negative bias established by  $V_{GS}$ , a level of recombination between electrons and holes will occur that will reduce the number of free electrons in the n-channel available for conduction. The more negative the bias, the higher the rate of recombination. The resulting level of drain current is therefore reduced with increasing negative bias for  $V_{GS}$  as shown in Fig.



### SYMBOLS OF MOSFET



### enhancement-type mosfet

Although there are some similarities in construction and mode of operation between depletion-type and enhancement-type MOSFETs, the characteristics of the enhancement-type MOSFET are quite different from anything obtained thus far. The transfer curve is not defined by Shockley's equation, and the drain current is now cut off until the gate-to-source voltage reaches a specific magnitude. In particular, current control in an n-channel device is now effected by a positive gate-to-source voltage rather than the range of negative voltages encountered for n-channel JFETs and n-channel depletion-type MOSFETs.

If  $V_{GS}$  is set at 0 V and a voltage applied between the drain and source of the device of Fig. 5.31, the absence of an n-channel (with its generous number of free carriers) will result in a current of effectively zero amperes—quite different from the depletion-type MOSFET and JFET where  $I_D \approx I_{DSS}$ . It is not sufficient to have a large accumulation of carriers (electrons) at the drain and source (due to the n-doped regions) if a path fails to exist between the two. With  $V_{DS}$  some positive voltage,  $V_{GS}$  at 0 V, and terminal SS directly connected to the source, there are in fact two reverse-biased p-n junctions between the n-doped regions and the p-substrate to oppose any significant flow between drain and source. In Fig. 5.32 both  $V_{DS}$  and  $V_{GS}$  have been set at some positive voltage greater than 0 V, establishing the drain and gate at a positive potential with respect to the source.

The positive potential at the gate will pressure the holes (since like charges repel) in the p-substrate along the edge of the  $\text{SiO}_2$  layer to leave the area and enter deeper regions of the p-substrate, as shown in the figure. The result is a depletion region near the  $\text{SiO}_2$  insulating layer void of holes. However, the electrons in the p-substrate (the minority carriers of the material) will be attracted to the positive gate and accumulate in the region near the surface of the  $\text{SiO}_2$  layer. The  $\text{SiO}_2$  layer and its insulating qualities will prevent the negative carriers from being absorbed at the gate terminal. As  $V_{GS}$  increases in magnitude, the concentration of electrons near the  $\text{SiO}_2$  surface increases until eventually the induced n-type region can support a measurable flow between drain and source. The level of  $V_{GS}$  that results in the significant increase in drain current is called the threshold voltage and is given the symbol  $V_T$ . On specification sheets it is referred to as  $V_{GS(Th)}$ , although  $V_T$  is less unwieldy and will be used in the analysis to follow. Since the channel is nonexistent

with  $V_{GS}=0V$

Enhanced by the application of a positive gate-to-source voltage, this type of MOSFET is called an enhancement-type MOSFET. Both depletion- and enhancement-type MOS-FETs have enhancement-type regions, but the label was applied to the latter since it is its only mode of operation.

